

**Past Sunday E42 topics****Topical Area**

2016	Summary and Overview of QSA and the implications to ASTM E42 standards development	XPS
2015	A Surface Analysis Carol: the ghosts of surface analysis past, present, and future	SIMS, XPS, Atom Probe
2014	Part 1 - And the survey says ... Extracting information from the XPS survey scan Part 2 - Standards Implications from QSA 2014	XPS General Surface Analysis
2013	Charge Compensation in Ion and Electron Spectroscopy: Best Practices, Pitfalls, & New Developments	AES, XPS, SIMS
2012	QSA meeting – no workshop	
2011	Establishing Best Analytical Practice	General Surface Analysis

**Past Tuesday ASSD/E42 topics****Topical Area**

2019	What do we know about what we don't know? – A panel discussion The analysis problem and its assumptions (C.R. Brundle) Uncertainties and their effect on assumptions (A. Herrera-Gomez)	XPS
2018	A Tribute to the Careers of Barbara Garrison and Nicholas Winograd	SIMS
2017	Frontiers of Surface Analysis: J.J. Thompson's ghost: Modern SIMS developments enable interface engineering at the technology forefront. (Fred Stevie) On the origin of the surface analysis species: The shared DNA of ASSD and ASTM-E42 in the formation of the Symposium on Applied Surface Analysis and the Quantitative Surface Analysis Conference. (John Grant, Cedric Powell) SESSA unmasked (Cedric Powell)	SIMS ASSD/ASTM E42 XPS modeling
2016	Frontiers of Surface Analysis: Inherently Nano: Surface Analysis challenges and opportunities in the development of nano-science (Don Baer) The rate debate: Current state of gas cluster source use in surface analysis (Rasmus Havelund)	General surface analysis Sample Handling, Sputter etching
2015	When is "perfect" the enemy of "good enough"? Maintaining perspective in surface analysis.	XPS, AES, SIMS
2014	Gas Cluster Ion Sources: Shiny New Toy or Tool for Opening Up New Frontiers in Surface Analysis?	General Surface Analysis
2013	Plenary - In Situ Electron Spectroscopies Reveal Catalyst Structure and Initial Reaction Steps in Fischer-Tropsch Synthesis Panel Discussion - The Story Behind the Data: A Panel Discussion on What to Look For in Surface Analytical Data	Near Ambient-XPS General Surface Analysis
2012	XPS and Beyond: ISS, UPS, HIM, APT and other TLAs (Three Letter Acronyms)	Surface Analysis/Microscopy
2011	Challenges in SIMS: A Symposium in Honor of Sally Asher	SIMS